

High Resolution High Accuracy Contact / Lateral Force AFM Cantilevers HA_C series, each chip has 2 cantilevers, resonant frequency 37 kHz / 19 kHz, force constant 0.65 N/m / 0.26 N/m

Art. ID	TIPS-HA_C/300
Unit	300 separated chips
Deliverydetails	No Dangerous Good /not restricted

Description

High Resolution AFM Cantilevers HA_C series are designed for Contact mode and Lateral Force Mode applications. Each probe has 2 rectangular cantilevers. Typical Resonant Frequency 37kHz / 19kHz (dispersion $\pm 10\%$). Typical Force Constant 0.65N/m / 0.26N/m (dispersion $\pm 20\%$). Cantilever has Au reflective side coating to increase laser signal. Probes are also available with no coating as well as with conductive tip coating / Probes are packed in boxes with 15 and 50 pieces. Amount discount is included in the package price / High Accuracy composite ETALON probes combine the main features allowing to obtain high quality AFM images: Sharp tip - curvature radius < 10 nm. /// Resonance frequency, specified with high accuracy - $\pm 10\%$ within a wafer. /// Special chip geometry with vertical sidewalls for convenient operating. /// High aspect ratio tip. /// Enhanced back-side reflection of the cantilever. /// Cost effective price